

Group 10.

Preparation:

- Sharpen the tip by cutting a wire and ~~putting~~ use it as tip.
- Take a sample of the material with adhesive film, obtaining a sample with a few hundred layers.
- Use the manual screw to approach the tip to the material, then use the motor to approach.
- Once the tip is close enough we can remove the motor and start measuring.

Measurements:

Task 1: Area scanning counting steps.

P: 0.15 I = 0.075

$V_{bias} = 1V$

Size: 20nm and 30nm Speed: 0.7 lines/s

$I_{set} = 1nA$

Task 2: Find a flat surface for atomic resolution

Resolution: ²⁵⁶ was increased to 512px Bias = ~~100~~ -10 mV

P = ^{0.15} ~~0.15~~ Size = 3nm $I_{set} = 2 - 6 nA$ and -50mV to -10mV

Task 3: Calibration of P and I:

1st: P = 0.3 I = 0.15 2nd: P = 0.6 I = 0.3

Size = 3nm Speed = 1 line/s

Size = 3nm Speed = 1 line/s

3rd: P = 0.9 I = 0.45 4th: P = 1.2 I = 0.6

Size = 3nm Speed = 1 line/s

Size = 3nm Speed = 1 line/s

Atomic resolution could not be achieved. The tip was not sharp enough to achieve such resolution.